STACKED TCH LOW ESR HERMETIC SERIES

SMD Low ESR Tantalum Capacitors with Conductive Polymer Electrode in Hermetic Package



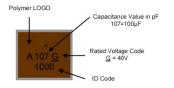


FEATURES

- · Aerospace & Hi-Rel applications
- Low ESR conductive polymer electrode
- High endurance
- Ceramic case hermetic packaging
- Stability under humidity and ambient atmosphere exposure
- Extremely low ESR and high footprint efficiency
- Based on hermetically sealed design developed with ESA to suit aerospace applications

MARKING

S CASE

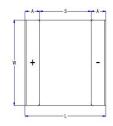


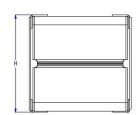
APPLICATIONS

- Aerospace
- Defence
- Power supplies
- Pulse power

CASE DIMENSIONS: millimeters (inches)

Code	Туре	L	W	H Max.	W ₁	S Min.
S	J-lead (L-shape)	11.80 ± 0.50 (0.465 ± 0.020)	12.50 ± 0.50 (0.492 ± 0.020)	12.40 (0.488)	2.05 ± 0.50 (0.081 ± 0.020)	7.00 (0.276)





HOW TO ORDER

KYOCERA AVX PART NUMBER

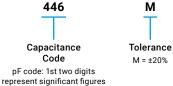








3rd digit represents multiplier (number of zeros to follow)













Not RoHS Compliant

TECHNICAL SPECIFICATIONS

Technical Data:	A	All technical data relate to an ambient temperature of +25°C									
Capacitance Range:		4.4μF to 660μF									
Capacitance Tolerance:	±	±20%									
Leakage Current DCL:	().1CV									
Rated Voltage (V _R)	≤ +85°C:	10	16	25	35	50	75	100			
Category Voltage (V _c)	≤ +125°C:	7	11	17	23	33	50	66			
Temperature Range:	-	55°C to +12	5°C				•				
Reliability:	1	% per 1000	hours at 85°C,	, Vr with 0.1Ω/	V series impe	dance, 60% co	nfidence leve	d			
Termination Finish:		SnPb Plating									
Typical Weight:	Ę	5.7g		-							

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CAPACITANCE AND VOLTAGE RANGE (CASE CODE BEFORE THE BRACKETS)

Capacitance		Rated Voltage DC (VR) at 85°C										
μF	Code	10V (A)	16V (C)	25V (E)	35V (V)	50V (T)	75V (<u>P</u>)	100V (<u>A</u>)				
44	446							S(100)				
66	666						S(80)					
88	886					S(50)						
200	207				S(40)							
300	307			S(40)	S(40)							
440	447		S(30)									
660	667	S(30)										

Stacked Capability - contact manufacturer

RATINGS & PART NUMBER REFERENCE

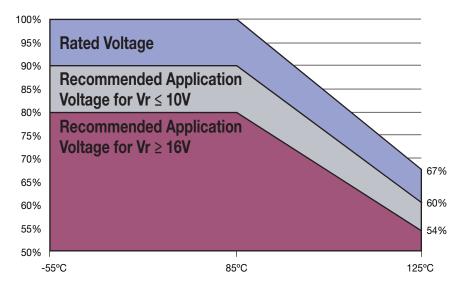
Part No.	Case Size	Capacitance (µF)	Rated Voltage (V)	Rated Temperature (°C)	Category Voltage (V)	Category Temperature (°C)	DCL Max. (µA)	DF Max. (%)	ESR Max. @ 100kHz		OkHz Ri Current (MSL
					(•)	(3)	(PA)	(,0)	(mΩ)	25°C	85°C	125°C	
10 Volt @ 85°C													
TCHS667M010W0030L	S	660	10	85	7	125	660	8	30	3.65	3.29	1.46	1
16 Volt @ 85°C													
TCHS447M016W0030L	S	440	16	85	11	125	704	8	30	3.65	3.29	1.46	1
	25 Volt @ 85°C												
TCHS307M025W0040L	S	300	25	85	17	125	750	8	40	3.16	2.84	1.26	1
					35 Volt @ 85	°C							
TCHS207M035W0040L	S	200	35	85	23	125	700	8	40	3.16	2.84	1.26	1
TCHS307M035W0040L	S	300	35	85	23	125	1050	8	40	3.16	2.84	1.26	1
					50 Volt @ 85	°C							
TCHS886M050W0050L	S	88	50	85	33	125	440	8	50	2.83	2.55	1.13	1
	75 Volt @ 85°C												
TCHS666M075W0080L	S	66	75	85	50	125	495	8	80	2.24	2.02	0.90	1
				1	00 Volt @ 85	s°C							
TCHS446M100W0100L	S	44	100	85	66	125	440	8	100	2.00	1.80	0.80	1

All technical data relates to an ambient temperature of +25°C. Capacitance and DF are measured at 120Hz, 0.5 RMS with a maximum DC bias of 2.2V. DCL is measured at rated voltage after 5 minutes.

Moisture Sensitivity Level (MSL) is defined according to J-STD-020.

RECOMMENDED DERATING FACTOR

Voltage and temperature derating as percentage of Vr



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QUALIFICATION TABLE

TEST	Stacked TCH Low ESR Hermetic Series (Temperature Range -55°C to +125°C)												
1201		Cond	ition	Characteristics									
				Visual examination	no visible damage								
			ted voltage for 2000 (10,000) leaving min. 2 hours at room	DCL	1.25 x initial limit								
Endurance	temperati	ure. Also determine of 1	25°C temperature, category	ΔC/C	within ±20% of initial value								
			nd then leaving min. 2 hours at r impedance to be < 3 Ω .	DF	1.5 x initial limit								
				ESR	2 x initial I	2 x initial limit							
				Visual examination	no visible	damage	,						
				DCL	2 x initial I	imit							
Storage Life		25°C, no voltage applie perature for 1-2 hours l	d, for 2000 hours. Stabilize at	ΔC/C	within ±20% of initial value								
	Toom tem	iperature for 1 2 flours i	Service measuring.	DF	1.5 x initial limit								
				ESR	2 x initial limit								
				Visual examination	no visible damage								
	Ctoro et 4	OOC and OOV relative by	unaidity for E6 days with no	DCL	1.25 x initial limit								
Humidity	applied vo	oltage. Stabilize at room	umidity for 56 days, with no n temperature and humidity for	ΔC/C	within ±10	within ±10% of initial value							
	min. 2 ho	urs before measuring.		DF	initial limit								
				ESR	1.25 x initial limit								
	Step	Temperature°C	Duration (min)		+20°C	-55°C	+20°C	+85°C	+125°C	+20°C			
	1	+20	15	DCL	*	n/a	*	10 x IL*	12.5 x IL*	*			
Temperature	3	-55 +20	15 15	ΔC/C	IL*	+0/-20%	±5%	+20/-0%	+30/-0%	±5%			
Stability	4	+85	15 15										
	5	+125	15	DF	IL*	1.5 x IL*	IL*	1.5 x IL*	2 x IL*	IL*			
	6	+20	15	ESR	1.25 x IL*	1.25 x IL*	1.25 x IL*	1.5 x IL*	1.5 x IL*	1.25 x IL*			
				Visual examination	no visible damage								
	Surge vol	oerature: 85°C+3/0°C tage: 1.15 x rated voltag		DCL	initial limit								
Surge Voltage	Discharge	otection resistance: 100 e resistance: 1000 Ω of cycles: 1000x	ΔC/C	within ±20% of initial value									
		ation: 6 min; 30 sec cha 5 min; 30 sec disc	DF	initial limit									
		5 mm, 55 555 disk	ESR	1.25 x initial limit									

^{*}Initial Limit